

<b>Notice of References Cited</b>	Application/Control No. 10/733,205		Applicant(s)/Patent Under Reexamination HAN ET AL.	
	Examiner Henry N. Tran		Art Unit 2629	Page 1 of 1

**U.S. PATENT DOCUMENTS**

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-7,077,543	07-2006	Nishiyama et al.	362/225
*	B	US-6,812,916	11-2004	Hwang, Beom Young	345/102
*	C	US-6,094,015	07-2000	Wessels et al.	315/291
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	K	US-			
	L	US-			
	M	US-			

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**NON-PATENT DOCUMENTS**

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